

High Aspect Ratio Si Pillars Etch

Pillar Diameter: 1.0-1.5 μm
Etching Mask: 50 nm Al

Process Condition

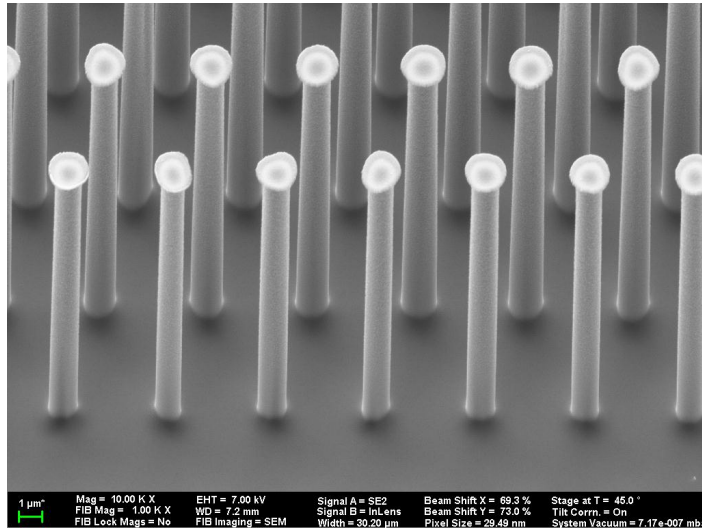
| Parameter | Value |
|--|----------|
| C4F8 (sccm) | 160 |
| SF6 (sccm) | 70 |
| Pressure (mTorr) | 20 |
| Coil Power (W) | 1200 |
| Platen Power (W) | 12 |
| Temperature ($^{\circ}\text{C}$) (lid/wall/chuck) | 40/40/21 |

Result

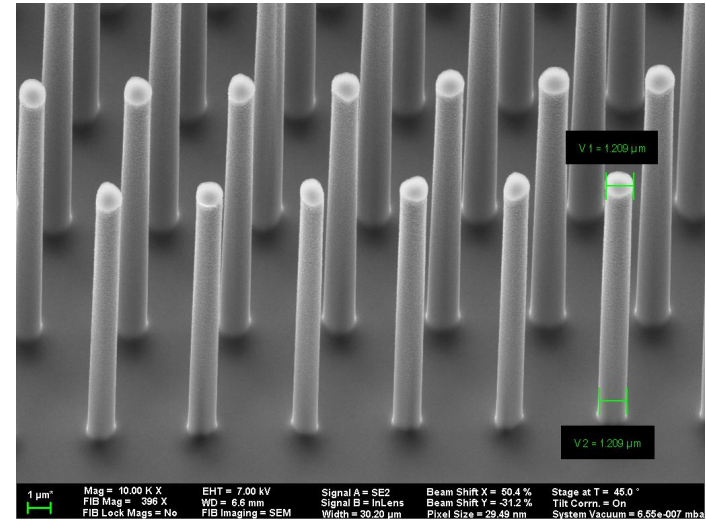
| | |
|--|-----------------|
| Etch Rate ($\mu\text{m}/\text{min}$) | 0.17 |
| Etch Profile | 89.5 $^{\circ}$ |
| Selectivity to Al | >100:1 |

Note: Profile = $\tan^{-1}(2H/(D_b - D_t))$,
H: etch depth, D_t = top diameter, D_b = bottom diameter
Selectivity = etch rate of Si/etch rate of Al

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10μm in depth and 1.2-1.5 μm in diameter Si pillars, before Al mask was removed



After Al mask was removed